TEST REPORT

Report No. A-035-15-V Date of Issue: 22 January 2016

Department of Defense Interface Standard Military Standard 461 ☐E ☒F

This test report is to certify that the device was tested according to the requirements of the above.
The results of this report should not be construed to imply compliance of devices other than the sample tested.
Without the laboratory approval by the documents, this report should not be copied in part.

1. Applicant

Company Name : IT Products Business Division, AVC Networks Company, Panasonic Corporation

Mailing Address : 1-10-12 Yagumo-higashi-machi, Moriguchi City, Osaka 570-0021, Japan

2. Identification of Tested Device

Device Name : Personal Computer
Model Number : CF-31
Serial Number : 4LKSA00506
Trade Name : Panasonic
Type of Test : ☒ Product Validation ☐ Design Validation ☐ Development Purpose
Test Plan Number : KEC-G111A_A-035-15-V Date:2015-11-18
Modification of Test Plan : ☒ No ☐ Yes (refer to deviation information in this report)

3. Test Items and Procedure

CE101	conducted emissions, power leads, 30Hz to 10kHz	☒ Pass	☐ Fail	☐ N/A
CE102	conducted emissions, power leads, 10kHz to 10MHz	☒ Pass	☐ Fail	☐ N/A
CS101	conducted susceptibility, power leads, 30Hz to 150kHz	☒ Pass	☐ Fail	☐ N/A
CS106	conducted susceptibility, transients, power leads	☐ Pass	☐ Fail	☒ N/A (*3)
CS114	conducted susceptibility, bulk cable injection, 10kHz to 200MHz	☒ Pass	☐ Fail	☐ N/A
CS115	conducted susceptibility, bulk cable injection, impulse excitation	☒ Pass	☐ Fail	☐ N/A
CS116	conducted susceptibility, damped sinusoidal transients, cables and power leads, 10kHz to 100MHz	☒ Pass	☐ Fail	☐ N/A
RE101	radiated emissions, magnetic field, 30Hz to 100kHz	☒ Pass	☐ Fail	☐ N/A
RE102	radiated emissions, electric field, 10kHz to 18GHz	☒ Pass	☐ Fail	☐ N/A
RS101	radiated susceptibility, magnetic field, 30Hz to 100kHz	☒ Pass	☐ Fail	☐ N/A
RS103	radiated susceptibility, electric field, 2MHz to 40GHz	☒ Pass	☐ Fail	☐ N/A

Refer the below reason(s) with respect to the decision and justification not to test.
(*1) DUT Specification (*2) Request of Applicant (*3) According to Test Plan (*4) Not Included in This Report

KEC Electronic Industry Development Center Testing Division
3-2-2, Hikari-dai, Seika-cho, Soraku-gun, Kyoto 619-0237 Japan

Test Engineer(s)

H'okamoto

Hironori Okamoto

ilac-MRA LAB JAB Testing RTL02810

Approved by Ikuya Minematsu / Group Manager